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	Filing Date		2004-03-30	
	First Named Inventor	Xiaolei Shi et al.		
	Art Unit	1795		
	Examiner Name	Anna L. Verderame		
Attorney Docket Number		140264-1		

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1	T. D. Krauss et al., "Femtosecond measurement of nonlinear absorption and refraction in CdS, ZnSe, and ZnS," American Institute of Physics, Volume 65, No. 14, October 3, 1994.	<input type="checkbox"/>
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